## IN THE CLAIMS:

Please amend Claims 5, 19, and 20 as shown below.

- 1. (Original) An organic semiconductor element comprising a gate electrode, a gate insulating layer, an organic semiconductor layer, source/drain electrodes and a protective film which are provided on a surface of a substrate, wherein an island-shaped protrusion layer having dispersed and island-shaped protrusions with a low surface energy is provided in contact with the organic semiconductor layer.
- 2. (Original) The organic semiconductor element according to claim 1, wherein between the gate insulating layer and the organic semiconductor layer is provided the island-shaped protrusion layer having the dispersed and island-shaped protrusions with the low surface energy.
- 3. (Original) The organic semiconductor element according to claim 1, wherein the gate electrode, the gate insulating layer, the island-shaped protrusion layer having the dispersed and island-shaped protrusions with the low surface energy, the organic semiconductor layer, the source/drain electrodes, and the protective film are formed in the mentioned order on the surface of the substrate.
- 4. (Original) The organic semiconductor element according to claim 1, wherein the gate electrode, the gate insulating layer, the organic semiconductor layer, the

island-shaped protrusion layer having the dispersed and island-shaped protrusions with the low surface energy, the source/drain electrodes, and the protective film are formed in the mentioned order on the surface of the substrate.

- 5. (Currently Amended) The organic semiconductor element according to claim 1, wherein the gate electrode, the gate insulating layer, the source/drain electrodes, the and island-shaped protrusion layer having the island-dispersed shaped protrusions with the low surface energy, the organic semiconductor layer, and the protective film are formed in the mentioned order on the surface of the substrate.
- 6. (Original) The organic semiconductor element according to claim 1, wherein the gate electrode, the gate insulating layer, any one of the source/drain electrodes, the island-shaped protrusion layer having the dispersed and island-shaped protrusions with the low surface energy, the organic semiconductor layer, the other of the source/drain electrodes, and the protective film are formed in the mentioned order on the surface of the substrate.
- 7. (Original) The organic semiconductor element according to claim 1, wherein a surface energy of the island-shaped protrusions is 30 dyn/cm<sup>2</sup> or less.
- 8. (Original) The organic semiconductor element according to claim 1, wherein a proportion of the island-shaped protrusions dispersed in the island-shaped

protrusion layer is 10 to 95% in relation to the whole island-shaped protrusion layer.

- 9. (Original) The organic semiconductor element according to claim 1, wherein each height of the island-shaped protrusions is 0.2 to 150 nm.
- 10. (Original) The organic semiconductor element according to claim 1, wherein an average diameter of the island-shaped protrusions is 0.1 to 100 nm.
- 11. (Original) The organic semiconductor element according to claim 1, wherein the island-shaped protrusions with the low surface energy are made of polyamide or polyimide.
- 12. (Original) The organic semiconductor element according to claim 1, wherein the island-shaped protrusions with the low surface energy are made of a fluorine-based polymer selected from the group consisting of polyfumarate-based polymers and cyclic perfluoropolymers.
- 13. (Original) The organic semiconductor element according to claim 1, wherein the island-shaped protrusions with the low surface energy are made of a fluorine-based compound selected from the group consisting of fluoroalkylsilane compounds and perfluoroether based compounds.

- 14. (Original) The organic semiconductor element according to claim 1, wherein the organic semiconductor layer is made of pentacene or tetracene.
- 15. (Original) The organic semiconductor element according to claim 1, wherein the organic semiconductor layer has periodicity with respect to a surface normal direction of the gate insulating layer.
- 16. (Original) The organic semiconductor element according to claim 1, wherein the organic semiconductor layer is made of a film of a pentacene derivative and a C-axis orientation ratio of the film of the pentacene derivative is 85% or more.
- 17. (Original) A production method of an organic semiconductor element, comprising providing on a surface of a substrate a gate electrode, a gate insulating layer, an organic semiconductor layer, source/drain electrodes and a protective film, wherein an island-shaped protrusion layer having dispersed and island-shaped protrusions with a low surface energy is formed in contact with the organic semiconductor layer by forming the island-shaped protrusions in a dispersed manner by spin coating or spray coating.
- 18. (Original) The production method according to claim 17, wherein after forming the island-shaped protrusion layer having the dispersed and island-shaped protrusions with the low surface energy, which are formed by the spin coating or spray coating, the organic semiconductor layer is formed on the island-shaped protrusion layer

under a heating condition of 60°C to 200°C.

- 19. (Currently Amended) An active matrix type display device comprising an organic semiconductor element according to claim 1 utilizing utilized as an active element.
- 20. (Currently Amended) An organic semiconductor device comprising an organic semiconductor element according to claim 1 as utilizing utilized as an IC information electronic tag.